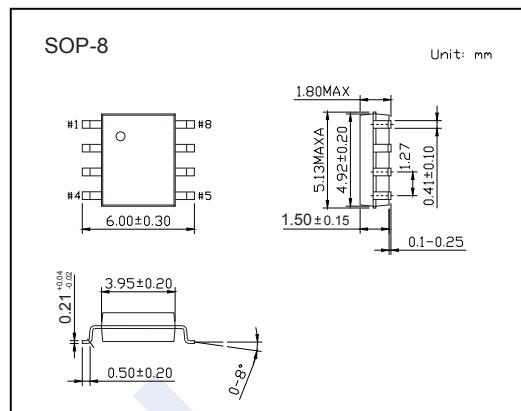
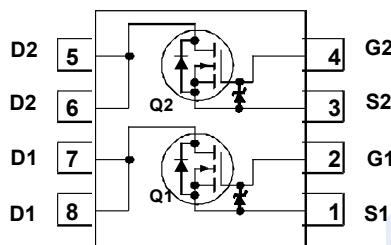


N-Channel Enhancement MOSFET

FDS89161 (KDS89161)

■ Features

- V_{DS} (V) = 100V
- I_D = 2.7 A
- $R_{DS(ON)} < 105\text{m}\Omega$ ($V_{GS} = 10\text{V}$)
- $R_{DS(ON)} < 160\text{m}\Omega$ ($V_{GS} = 4.5\text{V}$)
- High performance trench technology for extremely low $r_{DS(on)}$
- CDM ESD Protection Level > 2KV typical

■ Absolute Maximum Ratings $T_a = 25^\circ\text{C}$

| Parameter | Symbol | Rating | Unit |
|--|------------|------------|------|
| Drain-Source Voltage | V_{DS} | 100 | V |
| Gate-Source Voltage | V_{GS} | ± 20 | |
| Continuous Drain Current | I_D | 2.7 | A |
| Pulsed | | 15 | |
| Single Pulse Avalanche Energy (Note1) | E_{AS} | 13 | mJ |
| Power Dissipation | P_D | 31 | W |
| $T_c=25^\circ\text{C}$ | | 1.6 | |
| Thermal Resistance.Junction- to-Ambient | R_{thJA} | 78 | °C/W |
| Thermal Resistance.Junction- to-Case | R_{thJC} | 4 | |
| Junction Temperature | T_J | 150 | °C |
| Storage Temperature Range | T_{stg} | -55 to 150 | |

Note 1.Starting $T_J = 25^\circ\text{C}$, $L = 0.3 \text{ mH}$, $I_{AS} = 25 \text{ A}$, $V_{DD} = 27 \text{ V}$, $V_{GS} = 10\text{V}$.

2. $78^\circ\text{C}/\text{W}$ when mounted on a 1 in2pad of 2 oz copper

N-Channel Enhancement MOSFET

FDS89161 (KDS89161)

■ Electrical Characteristics Ta = 25°C

| Parameter | Symbol | Test Conditions | Min | Typ | Max | Unit |
|---|--------------------------------------|---|-----|-----|-----|-------|
| Drain-Source Breakdown Voltage | V _{DSS} | I _D =250 μ A, V _{GS} =0V | 100 | | | V |
| Breakdown Voltage Temperature coefficient | △V _{DSS} /△T _J | I _D =250 μ A, referenced to 25°C | | 68 | | mV/°C |
| Zero Gate Voltage Drain Current | I _{DSS} | V _{DS} =80V, V _{GS} =0V | | | 1 | μ A |
| Gate-Body Leakage Current | I _{GSS} | V _{DS} =0V, V _{GS} =±20V | | | ±10 | nA |
| Gate Threshold Voltage | V _{GS(th)} | V _{DS} =V _{GS} , I _D =250 μ A | 1 | 1.7 | 2.2 | V |
| Gate to Source Threshold Voltage Temperatture Coefficient | △V _{GS(th)} △T _J | I _D =250 μ A, referenced to 25°C | | -6 | | mV/°C |
| Static Drain-Source On-Resistance | R _{D(on)} | V _{GS} =10V, I _D =2.7A | | 81 | 105 | mΩ |
| | | V _{GS} =4.5V, I _D =2.1A | | 110 | 160 | |
| | | V _{GS} =10V, I _D =2.7A T _J =125°C | | 140 | 182 | |
| Forward Transconductance | g _F | V _{DS} =10V, I _D =2.7A | | 7.8 | | S |
| Input Capacitance | C _{iss} | V _{GS} =0V, V _{DS} =50V, f=1MHz | | 227 | 302 | pF |
| Output Capacitance | C _{oss} | | | 44 | 58 | |
| Reverse Transfer Capacitance | C _{rss} | | | 3 | 4 | |
| Gate Resistance | R _g | | | 0.9 | | Ω |
| Total Gate Charge | Q _g | V _{GS} =0 to 10V | | 3.8 | 5.3 | nC |
| | | V _{GS} =0 to 5V | | 2.1 | 2.9 | |
| Gate Source Charge | Q _{gs} | V _{DS} =50V, I _D =2.7A | | 0.7 | | nC |
| Gate Drain Charge | Q _{gd} | | | 0.7 | | |
| Turn-On DelayTime | t _{d(on)} | V _{GS} =10V, V _{DS} =50V, I _D =2.7A, R _{GEN} =6 Ω | | 3.8 | 10 | ns |
| Turn-On Rise Time | t _r | | | 1.2 | 10 | |
| Turn-Off DelayTime | t _{d(off)} | | | 9.5 | 17 | |
| Turn-Off Fall Time | t _f | | | 1.6 | 10 | |
| Body Diode Reverse Recovery Time | t _{rr} | I _F = 2.7A, dI/dt= 100A/ μ s | | 31 | 56 | nC |
| Body Diode Reverse Recovery Charge | Q _{rr} | | | 20 | 36 | |
| Diode Forward Voltage (Note 1) | V _{SD} | I _S =2.7A, V _{GS} =0V | | 0.8 | 1.3 | V |
| | | I _S =2A, V _{GS} =0V | | 0.8 | 1.2 | |

Note 1.Pulse Width < 300μs, Duty cycle < 2.0%.

N-Channel Enhancement MOSFET

FDS89161 (KDS89161)

■ Typical Characteristics

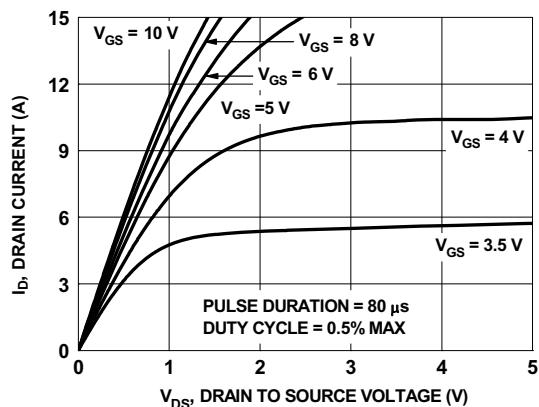


Figure 1. On-Region Characteristics

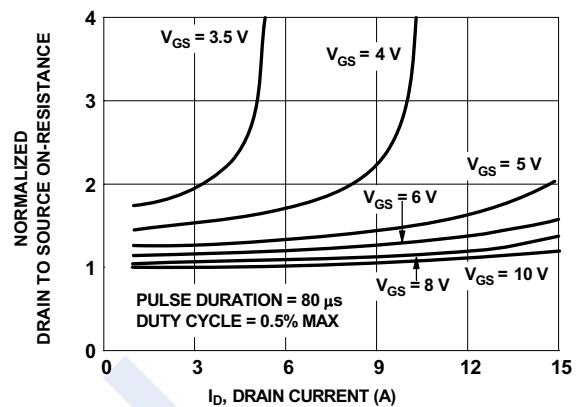


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

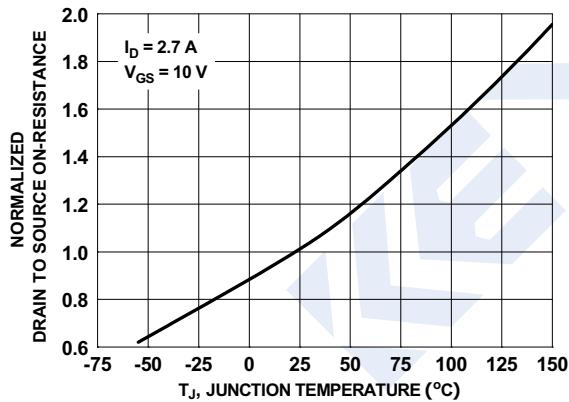


Figure 3. Normalized On-Resistance vs Junction Temperature

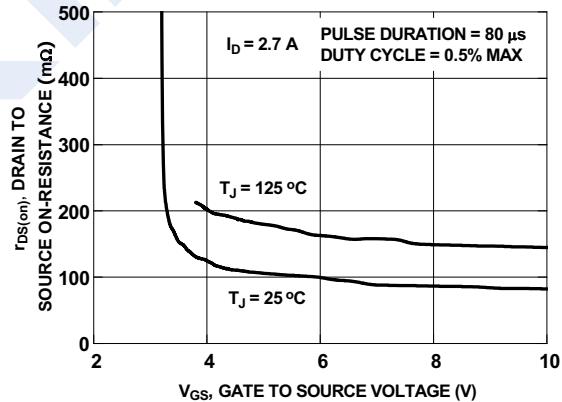


Figure 4. On-Resistance vs Gate to Source Voltage

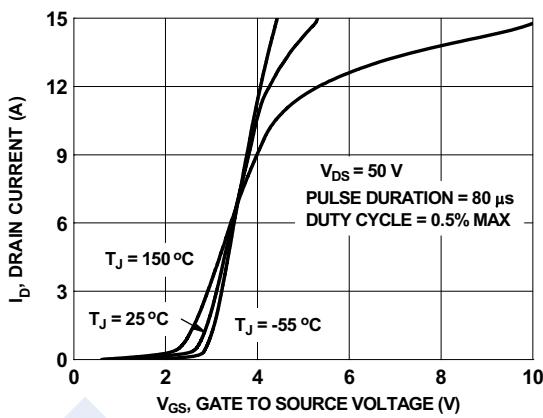


Figure 5. Transfer Characteristics

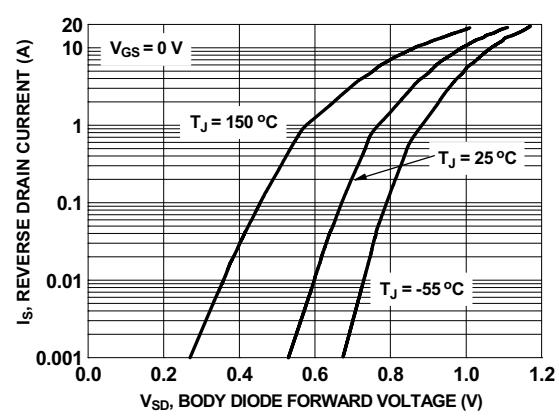


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

N-Channel Enhancement MOSFET

FDS89161 (KDS89161)

■ Typical Characteristics

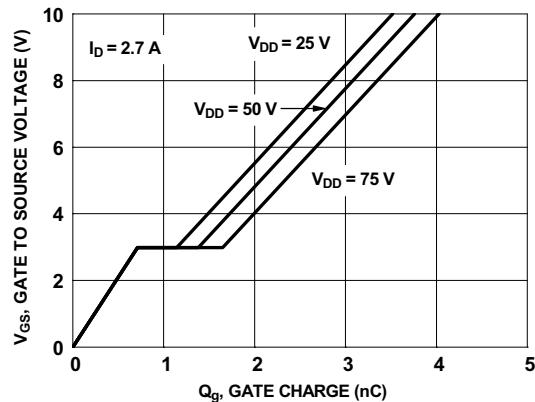


Figure 7. Gate Charge Characteristics

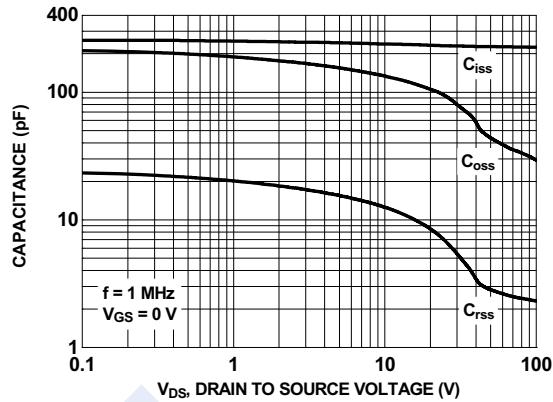


Figure 8. Capacitance vs Drain to Source Voltage

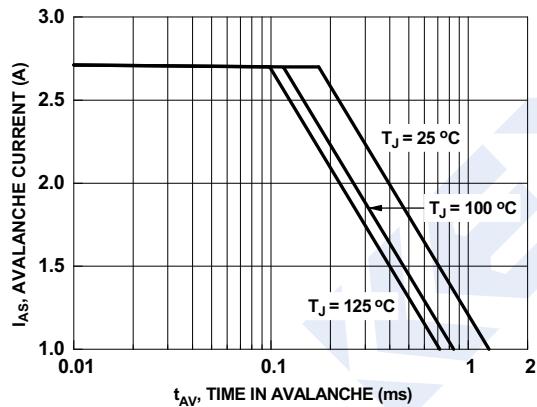


Figure 9. Unclamped Inductive Switching Capability

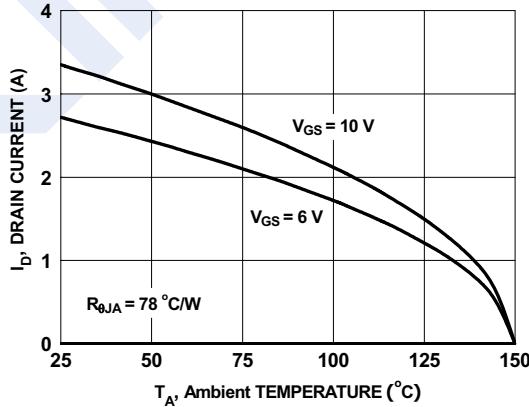


Figure 10. Maximum Continuous Drain Current vs Ambient Temperature

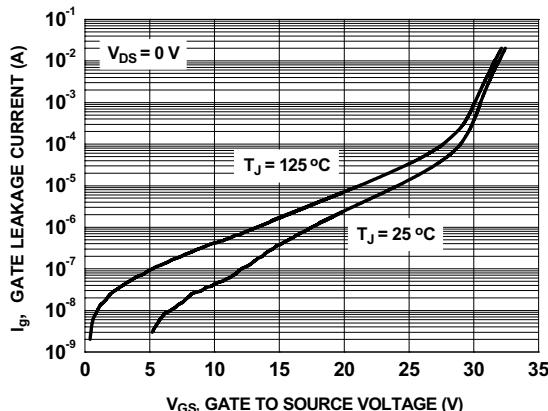


Figure 11. Gate Leakage Current vs Gate to Source Voltage

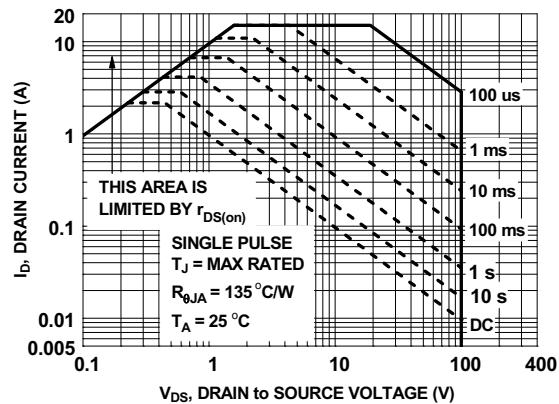


Figure 12. Forward Bias Safe Operating Area

N-Channel Enhancement MOSFET

FDS89161 (KDS89161)

■ Typical Characteristics

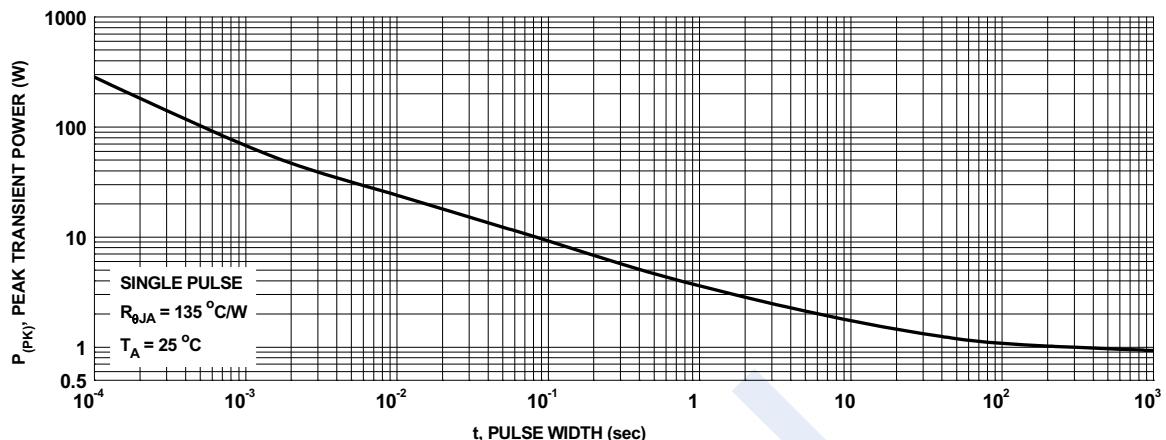


Figure 13. Single Pulse Maximum Power Dissipation

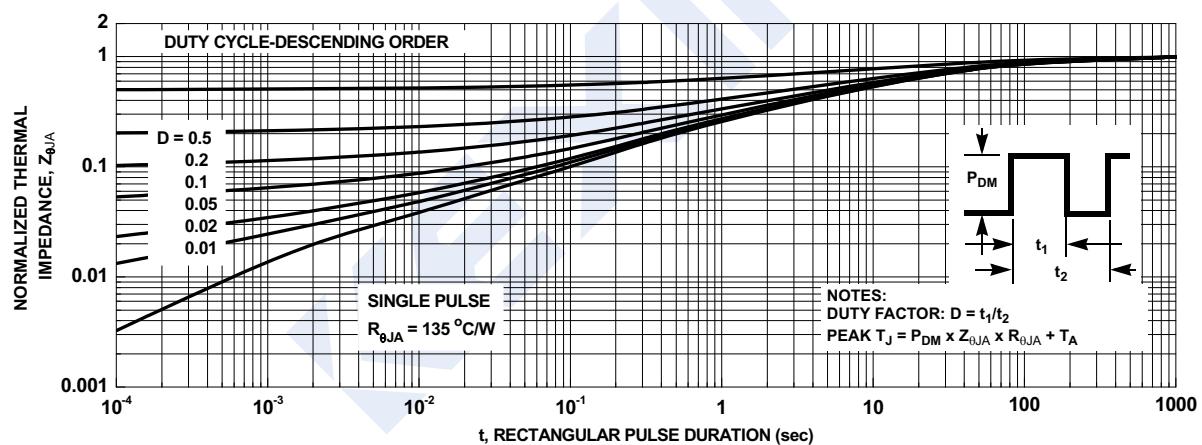


Figure 14. Junction-to-Ambient Transient Thermal Response Curve